

**Claims**

1. Method for the nondestructive measurement of the thickness of thin layers with a probe (11), which  
5 has a first coil device (14) on an inner core, the geometrical centre (22) of which coil device and the geometrical centre of at least a second coil device (31) coincide, the at least second coil device (31) partially surrounding the first coil  
10 device (24), with an evaluation unit, to which signals of the coil devices (24, 31) are emitted during a measurement for ascertaining the layer thickness, characterized in that a circuit (50) is provided, by which the first and the at least  
15 second coil device (24, 31) are excited sequentially during a measurement.
2. Method according to claim 1, characterized in that  
20 the coil devices (24, 31) are excited with high frequency.
3. Method according to claim 1 or 2, characterized in  
25 that the frequency signals coming from the first and at least second coil device (24, 31), which are emitted at separate times from one another, are limited by the period for the emission of the frequency signals of each coil device (24, 31) by  
30 means of transistors (54) which are preferably activated by the circuit (50) in analogy with the coil devices (24, 31).
4. Method according to claim 1, characterized in that  
35 the signals emitted by the coil devices (24, 31) are unequivocally assigned to the respective coil device (24, 31) and evaluated independently of one another by a series oscillating circuit (65).
5. Method according to claim 1, characterized in that  
the coil devices (24, 31) are excited with the same

**CERTIFICATE OF MAILING BY "EXPRESS MAIL" (37 CFR 1.10)**Applicant(s): **Rupe et al.**

Docket No.

**1706 (42059-01130)**

Serial No.

Not Yet Assigned

Filing Date

**March 27, 2001**

Examiner

Not Yet Assigned

Group Art Unit

Not Yet Assigned


Invention:

**SYSTEM AND METHOD FOR MODELING RESOURCES FOR CALLS CENTERED IN A PUBLIC SWITCH  
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Docket No.

(K) 54 084

Serial No.

Filing Date

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Group Art Unit

Invention: **METHOD AND APPARATUS FOR THE NONDESTRUCTIVE MEASUREMENT OF THE THICKNESS OF THIN LAYERS**

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**March 26, 2001***(Date)***M. Robert Kestenbaum***(Typed or Printed Name of Person Mailing Correspondence)**(Signature of Person Mailing Correspondence)***EF243721337US***("Express Mail" Mailing Label Number)***Note: Each paper must have its own certificate of mailing.**J1002 U.S. PRO  
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